

An IATF 16949, ISO9001 and ISO 14001 Certified Company

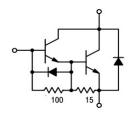




NPN SILICON POWER DARLINGTON TRANSISTOR

400 VOLTS 20 AMPERE 175 WATTS





MJ10005

TO-3
Metal Can Package
RoHS compliant

General Description

The MJ10005 Darlington transistor is designed for high–voltage, high–speed, power switching in inductive circuits where fall time is critical. It is particularly suited for line operated switchmode applications

FEATURES:

1. Fast Turn-Off Times

40 ns Inductive Fall Time @25° C (Typ)

650 ns Inductive Storage Time @ 25° C (Typ)

Operating Temperature Range -65 to +200° C

2. 100° C Performance Specified for: _

Reversed Biased SOA with Inductive Loads

Switching Times with Inductive Loads

Saturation Voltages

Leakage Currents

APPLICATION:

- 1. Switching Regulators
- 2. Inverters
- 3. Solenoid and Relay Drivers
- 4. Motor Controls
- 5. Deflection Circuits







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ABSOLUTE MAXIMUM RATINGS (T_a = 25 °C)

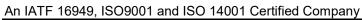
Rating	Symbol	Value	Unit
Collector–Emitter Voltage	V _{CEO}	400	Vdc
Collector–Emitter Voltage	V _{CEX}	450	Vdc
Collector–Emitter Voltage	V _{CEV}	500	Vdc
Emitter Base Voltage	V _{EB}	8.0	Vdc
Collector Current — Continuous — Peak (1)	Ic I _{CM}	20 30	Adc
Base Current — Continuous — Peak (1)	I _B	2.5 5.0	Adc
Total Power Dissipation @ T _C = 25°C @ T _C = 100°C Derate above 25°C	P _D	175 100 1.0	Watts W/°C
Operating and Storage Junction Temperature Range	T _J , T _{stg}	-65 to +200	°C

THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Case	R _{JC}	1.0	°C/W
Maximum Lead Temperature for Soldering Purposes 1/8 from Case for 5 Seconds	TL	275	°C

⁽¹⁾ Pulse Test: Pulse Width = 5.0 ms, Duty Cycle $\leq 10\%$.









ELECTRICAL CHARACTERISTICS at T_a = 25 °C

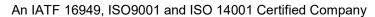
10 40	Symbol	Min	Тур	Max	Unit	
OFF CHARACTERIS	STICS					500
Collector–Emitter S (I _C = 250 mA, I _B	V _{CEO(sus)}	400	_	_	Vdc	
Collector Emitter S $(I_C = 2.0 \text{ A, V}_{clar})$ $(I_C = 10 \text{ A, V}_{clam})$	V _{CEX(sus)}	450 325	=	=	Vdc	
Collector Cutoff Cu (V _{CEV} = Rated V (V _{CEV} = Rated V	I _{CEV}	=	=	0.25 5.0	mAdc	
Collector Cutoff Cu (V _{CE} = Rated V _C	I _{CER}	-	: 	5.0	mAdc	
	Emitter Cutoff Current (V _{EB} = 2.0 Vdc, I _C = 0)			_	175	mAdc
SECOND BREAKD	OWN					
Second Breakdow	n Collector Current with base forward biased	I _{S/b}	~	See Fig	jure 11	
ON CHARACTERIS	TICS (2)					
DC Current Gain ($I_C = 5.0 \text{ Adc}, V_C$ ($I_C = 10 \text{ Adc}, V_C$		h _{FE}	50 40	=	600 400	_
Collector Emitter S (I _C = 10 Adc, I _B : (I _C = 20 Adc, I _B : (I _C = 10 Adc, I _B :	V _{CE(sat)}	=	=	1.9 3.0 2.0	Vdc	
Base Emitter Saturation Voltage (I _C = 10 Adc, I _B = 400 mAdc) (I _C = 10 Adc, I _B = 400 mAdc, T _C = 100°C)		V _{BE(sat)}	_	=	2.5 2.5	Vdc
Diode Forward Vol (I _F = 10 Adc)	tage (1)	V _f	_	3.0	5.0	Vdc
DYNAMIC CHARAC	TERISTICS	•				
Small–Signal Current Gain (I _C = 1.0 Adc, V _{CE} = 10 Vdc, f _{test} = 1.0 MHz)		h _{fe}	10	-	_	_
Output Capacitano (V _{CB} = 10 Vdc, I	e E = 0, f _{test} = 100 kHz)	C _{ob}	100	2. 	325	pF
SWITCHING CHAR	ACTERISTICS					
Resistive Load (T	able 1)					~
Delay Time		t _d	-	0.12	0.2	s
Rise Time	$(V_{CC} = 250 \text{ Vdc}, I_C = 10 \text{ A}, I_{B1} = 400 \text{ mA}, V_{BE(off)} = 5.0 \text{ Vdc}, t_p = 50 \text{ s},$	t _r		0.2	0.6	s
Storage Time	Duty Cycle \leq 2%).	t _s		0.6	1.5	s
Fall Time		t _f		0.15	0.5	s
Inductive Load Cl	amped (Table 1)					
Storage Time	(I _C = 10 A(pk), V _{clamp} = Rated V _{CEX} , I _{B1} = 400 mA,	t _{sv}		1.0	2.5	s
Crossover Time	$V_{BE(off)} = 5.0 \text{ Vdc}, T_C = 100^{\circ}\text{C})$	t _c	_	0.4	1.5	s
Storage Time	(I _C = 10 A(pk), V _{clamp} = Rated V _{CEX} , I _{B1} = 400 mA,	t _{sv}	_	0.65	-	s
Crossover Time	$V_{BE(off)} = 5.0 \text{ Vdc}, T_C = 25^{\circ}C)$	t _c		0.2	_	s

⁽¹⁾ The internal Collector-to-Emitter diode can eliminate the need for an external diode to clamp inductive loads. Tests have shown that the Forward Recovery Voltage (V_f) of this diode is comparable to that of typical fast recovery rectifiers. (2) Pulse Test: PW = 300 s, Duty Cycle $\leq 2\%$.

MJ10005

Rev0_28042020EM

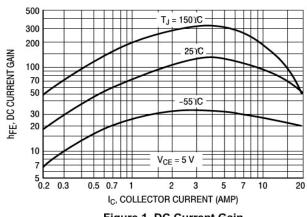








Typical Characteristic Curves



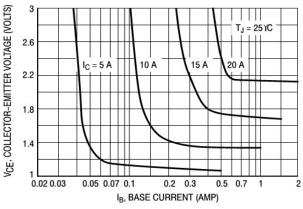
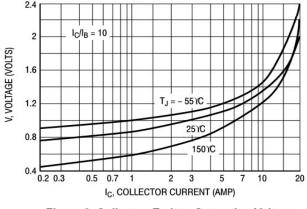


Figure 1. DC Current Gain

Figure 2. Collector Saturation Region



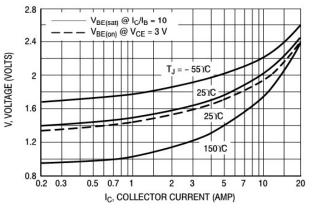
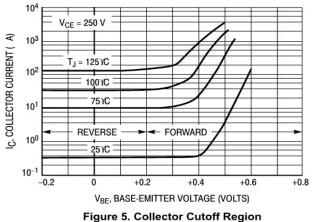


Figure 3. Collector-Emitter Saturation Voltage

Figure 4. Base-Emitter Voltage



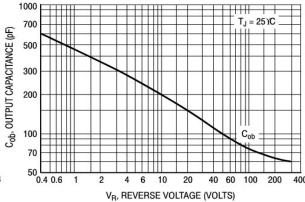


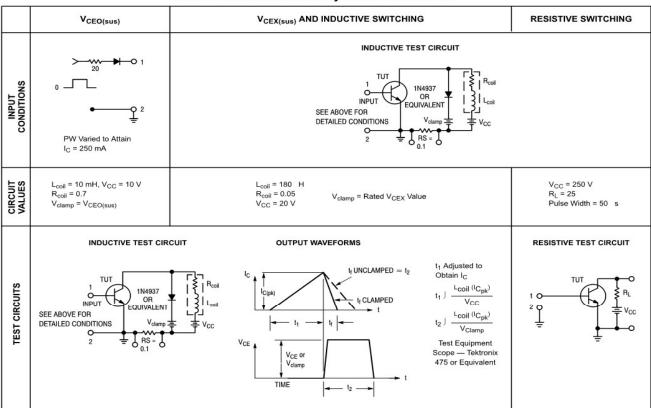
Figure 6. Output Capacitance





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Table 1. Test Conditions for Dynamic Performance



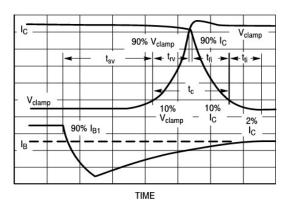
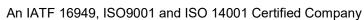


Figure 7. Inductive Switching Measurements









Typical Characteristic Curves

RESISTIVE SWITCHING PERFORMANCE

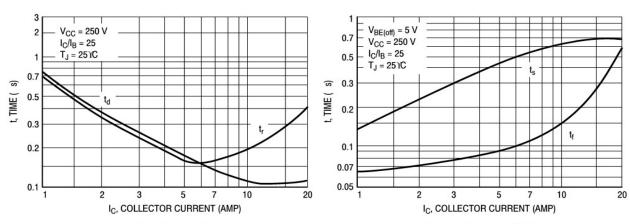


Figure 8. Turn-On Time

Figure 9. Turn-Off Time

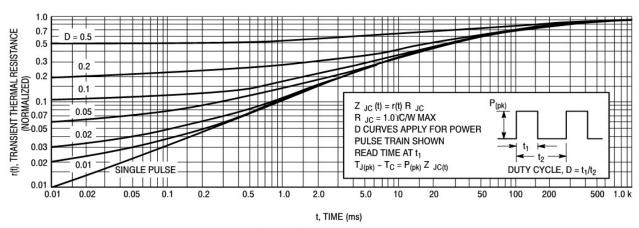
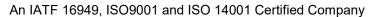


Figure 10. Thermal Response









Typical Characteristic Curves

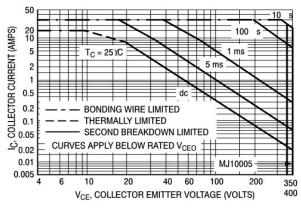


Figure 11. Forward Bias Safe Operating Area

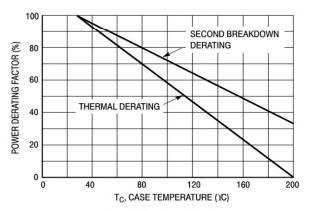


Figure 13. Power Derating

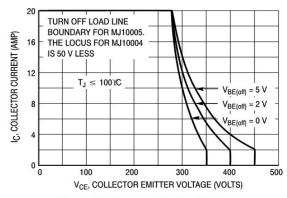


Figure 12. Reverse Bias Switching Safe Operating Area

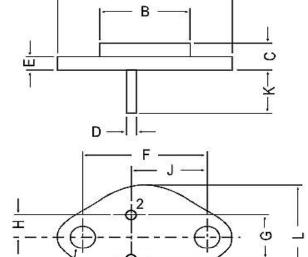






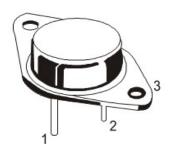


Package Details



All dimensions in mm.

DIM	MIN.	MAX.
Α		39.37
В	_	22.22
С	6.35	8.50
D	0.96	1.09
E	-	1.77
F	29.90	30.40
G	10.69	11.18
Н	5.20	5.72
J	16.64	17.15
K	11.15	12.25
L		26.67
М	3.84	4.19



PIN CONFIGURATION

- 1. BASE
- 2. EMITTER
- 3. COLLECTOR

Packing Detail

PACKAGE	STANDARD PACK		INNER CARTON BOX		OUTER CARTON BOX		
	Details	Net Weight/Qty	Size	Qty	Size	Qty	Gr Wt
TO-3	100 pcs/pkt	1.3 kg/100 pcs	12.5" x 8" x 1.8"	0.1K	17" x 11.5" x 21"	2K	27.5 kgs



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Recommended Product Storage Environment for Discrete Semiconductor Devices

This storage environment assumes that the Diodes and transistors are packed properly inside the original packing supplied by CDIL.

- · Temperature 5 °C to 30 °C
- · Humidity between 40 to 70 %RH
- · Air should be clean.
- · Avoid harmful gas or dust.
- · Avoid outdoor exposure or storage in areas subject to rain or water spraying .
- · Avoid storage in areas subject to corrosive gas or dust. Product shall not be stored in areas exposed to direct sunlight.
- Avoid rapid change of temperature.
- · Avoid condensation.
- · Mechanical stress such as vibration and impact shall be avoided.
- · The product shall not be placed directly on the floor.
- The product shall be stored on a plane area. They should not be turned upside down. They should not be placed against the wall.

Shelf Life of CDIL Products

The shelf life of products is the period from product manufacture to shipment to customers. The product can be unconditionally shipped within this period. The period is defined as 2 years.

If products are stored longer than the shelf life of 2 years the products shall be subjected to quality check as per CDIL quality procedure.

The products are further warranted for another one year after the date of shipment subject to the above conditions in CDIL original packing.

Floor Life of CDIL Products and MSL Level

When the products are opened from the original packing, the floor life will start.

For this, the following JEDEC table may be referred:

JEDEC MSL Level				
Level	Time	Condition		
1	Unlimited	≤30 °C / 85% RH		
2	1 Year	≤30 °C / 60% RH		
2a	4 Weeks	≤30 °C / 60% RH		
3	168 Hours	≤30 °C / 60% RH		
4	72 Hours	≤30 °C / 60% RH		
5	48 Hours	≤30 °C / 60% RH		
5a	24 Hours	≤30 °C / 60% RH		
6	Time on Label(TOL)	≤30 °C / 60% RH		







Customer Notes

Component Disposal Instructions

- 1. CDIL Semiconductor Devices are RoHS compliant, customers are requested to please dispose as per prevailing Environmental Legislation of their Country.
- 2. In Europe, please dispose as per EU Directive 2002/96/EC on Waste Electrical and Electronic Equipment (WEEE).

Disclaimer

The product information and the selection guides facilitate selection of the CDIL's Semiconductor Device(s) best suited for application in your product(s) as per your requirement. It is recommended that you completely review our Data Sheet(s) so as to confirm that the Device(s) meet functionality parameters for your application. The information furnished in the Data Sheet and on the CDIL Web Site/CD are believed to be accurate and reliable. CDIL however, does not assume responsibility for inaccuracies or incomplete information. Furthermore, CDIL does not assume liability whatsoever, arising out of the application or use of any CDIL product; neither does it convey any license under its patent rights nor rights of others. These products are not designed for use in life saving/support appliances or systems. CDIL customers selling these products (either as individual Semiconductor Devices or incorporated in their end products), in any life saving/support appliances or systems or applications do so at their own risk and CDIL will not be responsible for any damages resulting from such sale(s).

CDIL strives for continuous improvement and reserves the right to change the specifications of its products without prior notice.



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